

\* \* \* \* \* Welcome to STN International \* \* \* \* \*

<u>NEWS 1</u>		Web Page URLs for STN Seminar Schedule - N. America
<u>NEWS 2</u>		"Ask CAS" for self-help around the clock
<u>NEWS 3</u>	FEB 28	PATDPAFULL - New display fields provide for legal status data from INPADOC
<u>NEWS 4</u>	FEB 28	BABS - Current-awareness alerts (SDIs) available
<u>NEWS 5</u>	MAR 02	GBFULL: New full-text patent database on STN
<u>NEWS 6</u>	MAR 03	REGISTRY/ZREGISTRY - Sequence annotations enhanced
<u>NEWS 7</u>	MAR 03	MEDLINE file segment of TOXCENTER reloaded
<u>NEWS 8</u>	MAR 22	KOREAPAT now updated monthly; patent information enhanced
<u>NEWS 9</u>	MAR 22	Original IDE display format returns to REGISTRY/ZREGISTRY
<u>NEWS 10</u>	MAR 22	PATDPASPC - New patent database available
<u>NEWS 11</u>	MAR 22	REGISTRY/ZREGISTRY enhanced with experimental property tags
<u>NEWS 12</u>	APR 04	EPFULL enhanced with additional patent information and new fields
<u>NEWS 13</u>	APR 04	EMBASE - Database reloaded and enhanced
<u>NEWS 14</u>	APR 18	New CAS Information Use Policies available online
<u>NEWS 15</u>	APR 25	Patent searching, including current-awareness alerts (SDIs), based on application date in CA/CAPLUS and USPATFULL/USPAT2 may be affected by a change in filing date for U.S. applications.
<u>NEWS 16</u>	APR 28	Improved searching of U.S. Patent Classifications for U.S. patent records in CA/CAPLUS
<u>NEWS 17</u>	MAY 23	GBFULL enhanced with patent drawing images
<u>NEWS 18</u>	MAY 23	REGISTRY has been enhanced with source information from CHEMCATS
<u>NEWS 19</u>	JUN 06	The Analysis Edition of STN Express with Discover! (Version 8.0 for Windows) now available
<u>NEWS 20</u>	JUN 13	RUSSIAPAT: New full-text patent database on STN
<u>NEWS 21</u>	JUN 13	FRFULL enhanced with patent drawing images
<u>NEWS 22</u>	JUN 27	MARPAT displays enhanced with expanded G-group definitions and text labels
<u>NEWS 23</u>	JUL 01	MEDICONF removed from STN
<u>NEWS 24</u>	JUL 07	STN Patent Forums to be held in July 2005
<u>NEWS 25</u>	JUL 13	SCISEARCH reloaded
<u>NEWS 26</u>	JUL 20	Powerful new interactive analysis and visualization software, STN AnaVist, now available
<u>NEWS 27</u>	AUG 11	Derwent World Patents Index(R) web-based training during August
<u>NEWS 28</u>	AUG 11	STN AnaVist workshops to be held in North America
<u>NEWS 29</u>	AUG 30	CA/CAPLUS - Increased access to 19th century research documents
<u>NEWS 30</u>	AUG 30	CASREACT - Enhanced with displayable reaction conditions
<u>NEWS EXPRESS</u>	JUNE 13	CURRENT WINDOWS VERSION IS V8.0, CURRENT MACINTOSH VERSION IS V6.0c(ENG) AND V6.0Jc(JP), AND CURRENT DISCOVER FILE IS DATED 13 JUNE 2005
<u>NEWS HOURS</u>		STN Operating Hours Plus Help Desk Availability
<u>NEWS INTER</u>		General Internet Information
<u>NEWS LOGIN</u>		Welcome Banner and News Items
<u>NEWS PHONE</u>		Direct Dial and Telecommunication Network Access to STN
<u>NEWS WWW</u>		CAS World Wide Web Site (general information)

Enter NEWS followed by the item number or name to see news on that specific topic.

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\* \* \* \* \* STN Columbus \* \* \* \* \*

FILE 'HOME' ENTERED AT 15:52:54 ON 06 SEP 2005

=> file inspec

COST IN U.S. DOLLARS

SINCE FILE

TOTAL

ENTRY

SESSION

FULL ESTIMATED COST

0.21

0.21

FILE 'INSPEC' ENTERED AT 15:53:03 ON 06 SEP 2005

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FILE LAST UPDATED: 5 SEP 2005

<20050905/UP>

FILE COVERS 1969 TO DATE.

<<< SIMULTANEOUS LEFT AND RIGHT TRUNCATION AVAILABLE IN  
THE BASIC INDEX >>>

=> s nanotube cluster

6592 NANOTUBE

93315 CLUSTER

L1

2 NANOTUBE CLUSTER

(NANOTUBE (W) CLUSTER)

=> d l1 1-2

L1 ANSWER 1 OF 2 INSPEC (C) 2005 IEE on STN

Full Text

AN 2005:8494880 INSPEC DN A2005-17-6148-002; C2005-08-7320-138

TI Large-scale quantum-mechanical simulations of nanoscale devices and new materials.

AU Bernholc, J.; Nardelli, M.B.; Lu, W.; Nakhmanson, S. (Dept. of Phys., North Carolina State Univ., Raleigh, NC, USA); Meunier, V.

SO Proceedings. Users Group Conference

Los Alamitos, CA, USA: IEEE Computer Soc, 2004. p.34-8 of x+328 pp. 19 refs.

Conference: Williamsburg, VA, USA, 7-11 June 2004

Price: CCCC 0 7695 2259 9/2004/\$20.00

ISBN: 0-7695-2259-9

DT Conference Article

TC Practical; Application

CY United States

LA English

L1 ANSWER 2 OF 2 INSPEC (C) 2005 IEE on STN

Full Text

AN 2002:7423320 INSPEC DN A2002-23-7125X-001

TI Density-functional-theory calculations of charged single-walled carbon nanotubes.

AU Ji Luo; Peng, L.-M.; Xue, Z.Q.; Wu, J.L. (Dept. of Electron., Peking Univ., Beijing, China)

SO Physical Review B (Condensed Matter and Materials Physics) (15 Sept. 2002) vol.66, no.11, p.115415/1-5. 24 refs.

Doc. No.: S0163-1829(02)07135-7

Published by: APS through AIP  
 Price: CCCC 0163-1829/2002/66(11)/115415(5)/\$20.00  
 CODEN: PRBMDO ISSN: 0163-1829  
 SICI: 0163-1829(20020915)66:11L:1:DFTC;1-0

DT Journal  
 TC Theoretical  
 CY United States  
 LA English

=> **nanotube**

NANOTUBE IS NOT A RECOGNIZED COMMAND

The previous command name entered was not recognized by the system.  
 For a list of commands available to you in the current file, enter  
 "HELP COMMANDS" at an arrow prompt (=>).

=> **s nanotube**

L2 6592 NANOTUBE

=> **s conductive**

L3 21953 CONDUCTIVE

=> **s 12 and 13**

L4 105 L2 AND L3

=> **s trace**

L5 32396 TRACE

=> **s 14 and 15**

L6 0 L4 AND L5

=> **s substrate**

L7 177899 SUBSTRATE

=> **s 14 and 17**

L8 9 L4 AND L7

=> **d 18 1-9**

L8 ANSWER 1 OF 9 INSPEC (C) 2005 IEE on STN



AN 2004:8140681 INSPEC DN A2004-23-7970-018; B2004-11-2320-031

TI Field emission from thick carbon **nanotube** film on Si **substrate**.

AU Qikun Wang; Chang-Chun Zhu; Yongsheng Shi (Sch. of Electron. & Inf. Eng.,  
 Xi'an Jiaotong Univ., China)

SO Surface and Interface Analysis (May-June 2004) vol.36, no.5-6, p.478-80. 8  
 refs.

Published by: Wiley

Price: CCCC 0142-2421/04/\$30.00

CODEN: SIANDQ ISSN: 0142-2421

SICI: 0142-2421(200405/06)36:5/6L:478:FEFT;1-M

Conference: 48th International Field Emission Symposium. Lyon, France,  
 8-11 July 2002

Sponsor(s): Cameca; Club Technologie; CNRS (of France); Hamamatsu; IEEE  
 Electron Devices Soc.; MECA 2000; NaWoTec

DT Conference Article; Journal

TC Experimental

CY United Kingdom

LA English

L8 ANSWER 2 OF 9 INSPEC (C) 2005 IEE on STN



AN 2004:8109451 INSPEC DN B2004-10-2575-025  
 TI Integrating nano carbontubes with microchannel cooler.  
 AU Zhimin Mo; Anderson, J.; Liu, J. (SMIT Center & Div. of Electron.  
 Production, Chalmers Univ. of Technol., Molndal, Sweden)  
 SO Proceedings of the Sixth IEEE CPMT Conference on High Density Microsystem  
 Design and Packaging and Component Failure Analysis (HDP '04) (IEEE Cat.  
 No.04EX905)  
 Piscataway, NJ, USA: IEEE, 2004. p.373-6 of 393 pp. 9 refs.  
 Conference: Shanghai, China, 30 June-3 July 2004  
 Price: CCCC 0-7803-8620-5/04/\$17.00  
 ISBN: 0-7803-8620-5  
 DT Conference Article  
 TC Practical  
 CY United States  
 LA English

L8 ANSWER 3 OF 9 INSPEC (C) 2005 IEE on STN



AN 2004:7981790 INSPEC DN A2004-14-7360T-002  
 TI Synthesis and characterization of carbon **nanotube**-conducting polymer  
 thin films.  
 AU Ferrer-Anglada, N. (Departament de Fisica Aplicada, Univ. Politecnica de  
 Catalunya, Barcelona, Spain); Kaempgen, M.; Skakalova, V.;  
 Dettlaf-Weglikowska, U.; Roth, S.  
 SO Diamond and Related Materials (Feb. 2004) vol.13, no.2, p.256-60. 17 refs.  
 Published by: Elsevier  
 Price: CCCC 0925-9635/04/\$30.00  
 CODEN: DRMTE3 ISSN: 0925-9635  
 SICI: 0925-9635(200402)13:2L:256:SCCN;1-J  
 Conference: Carbon Materials for Active Electronics. Symposium L, E-MRS  
 Spring Meeting 2003. Strasbourg, France, 10-13 June 2003  
 DT Conference Article; Journal  
 TC Experimental  
 CY Netherlands  
 LA English

L8 ANSWER 4 OF 9 INSPEC (C) 2005 IEE on STN



AN 2004:7954675 INSPEC DN A2004-12-8120V-006  
 TI Percolation in multi-wall carbon **nanotube**-epoxy composites influence of  
 processing parameters, **nanotube** aspect ratio and electric fields on the  
 bulk conductivity.  
 AU Sandler, J.K.W.; Windle, A.H.; Martin, C.A. (Dept. of Mater. Sci. &  
 Metall., Cambridge Univ., UK); Schwarz, M.-K.; Bauhofer, W.; Schulte, K.;  
 Shaffer, M.S.P.  
 SO Continuous Nanophase and Nanostructured Materials Symposium (Mater. Res.  
 Soc. Symposium Proceedings Vol.788)  
 Editor(s): Komarneni, S.; Parker, J.C.; Watkins, J.J.  
 Warrendale, PA, USA: Mater. Res. Soc, 2004. p.221-6 of xvii+662 pp. 12  
 refs.  
 Conference: Boston, MA, USA, 1-5 Dec 2003  
 ISBN: 1-55899-726-1  
 DT Conference Article  
 TC Experimental

CY United States  
LA English

L8 ANSWER 5 OF 9 INSPEC (C) 2005 IEE on STN

Full Text	Links References
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AN 2004:7917669 INSPEC DN A2004-10-8115H-008; B2004-05-0520F-026  
 TI Selected-area growth of carbon nanotubes by the combination of focused ion beam and chemical vapor deposition techniques.  
 AU Jun Jiao; Lifeng Dong; Foxley, S.; Mosher, C.L.; Tuggle, D.W. (Dept. of Phys., Portland State Univ., OR, USA)  
 SO Microscopy and Microanalysis (Dec. 2003) vol.9, no.6, p.516-21. 11 refs.  
 Published by: Springer-Verlag  
 CODEN: MIMIF7 ISSN: 1431-9276  
 SICI: 1431-9276(200312)9:6L:516:SAGC;1-D  
 DT Journal  
 TC Experimental  
 CY United States  
 LA English

L8 ANSWER 6 OF 9 INSPEC (C) 2005 IEE on STN

Full Text	Links References
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AN 2004:7904475 INSPEC DN B2004-04-7260-011  
 TI Study to large area screen printing cathode of carbon **nanotube**.  
 AU Shi Yongsheng; Zhu Changchun; Wang Qikun (Sch. of Electron. & Inf. Eng., Xi'an Jiaotong Univ., China)  
 SO Journal of Xi'an Jiaotong University (Dec. 2003) vol.37, no.12, p.1304-7. 8 refs.  
 Published by: Editorial Board J. of Xi'an Jiaotong Univ  
 CODEN: HCTPDW ISSN: 0253-987X  
 SICI: 0253-987X(200312)37:12L:1304:SLAS;1-V  
 DT Journal  
 TC Application; Practical  
 CY China  
 LA Chinese

L8 ANSWER 7 OF 9 INSPEC (C) 2005 IEE on STN

Full Text	Links References
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AN 2004:7842628 INSPEC DN A2004-05-8120V-013; B2004-03-2320-004  
 TI Large area screen-printing cathode of CNT for FED.  
 AU Yong Sheng Shi; Chang-Chun Zhu; Wang Qikun; Li Xin (Sch. of Electron. & Inf. Eng., Xi'an Jiaotong Univ., China)  
 SO Diamond and Related Materials (Sept. 2003) vol.12, no.9, p.1449-52. 9 refs.  
 Published by: Elsevier  
 Price: CCCC 0925-9635/03/\$30.00  
 CODEN: DRMTE3 ISSN: 0925-9635  
 SICI: 0925-9635(200309)12:9L:1449:LASP;1-N  
 DT Journal  
 TC Experimental  
 CY Netherlands  
 LA English

L8 ANSWER 8 OF 9 INSPEC (C) 2005 IEE on STN

Full Text	Links References
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AN 2003:7799620 INSPEC DN A2004-02-8120V-006; B2004-01-0587-011  
 TI Low-temperature synthesis of large-area CNx **nanotube** arrays.

AU Dali Qian; Andrews, R.; Jacques, D.; Kichambare, P. (Center for Appl.  
Energy Res., Kentucky Univ., Lexington, KY, USA); Lian, G.; Dickey, E.C.  
SO Journal of Nanoscience and Nanotechnology (Feb.-April 2003) vol.3, no.1-2,  
p.93-7. 34 refs.  
Published by: American Scientific Publishers  
Price: CCCC 1533-4880/2003/01/093/005/\$17.00+.25  
CODEN: JNNOAR ISSN: 1533-4880  
SICI: 1533-4880(200302/04)3:1/2L.93:TSLA;1-S  
DT Journal  
TC Experimental  
CY United States  
LA English

L8 ANSWER 9 OF 9 INSPEC (C) 2005 IEE on STN

Full Text	Links References
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AN 2001:6879093 INSPEC DN B2001-05-2230F-001  
TI Field-emission device with carbon nanotubes for a flat panel display.  
AU Nakayama, Y.; Akita, S. (Dept. of Phys. & Electron., Osaka Prefectural  
Univ., Sakai, Japan)  
SO Synthetic Metals (15 Feb. 2001) vol.117, no.1-3, p.207-10. 10 refs.  
Doc. No.: S0379-6779(00)00365-9  
Published by: Elsevier  
Price: CCCC 0379-6779/2001/\$20.00  
CODEN: SYMEDZ ISSN: 0379-6779  
SICI: 0379-6779(20010215)117:1/3L.207:FEDW;1-7  
Conference: 10th Molecular Electronics and Devices Symposium (ME&D'99) and  
the International Workshop on Quantum Transport in Synthetic Metals  
(QTSM-1). Taejon and Seoul, South Korea, 8-11 May 1999  
DT Conference Article; Journal  
TC Practical; Experimental  
CY Switzerland  
LA English

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